Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/728,597	ENMEI, TOSHIHARU	
Examiner	Art Unit	
Madeleine AV Nguyen	2626	

	SEARCHED			
Class	Subclass	Date	Examiner	
update		1/21/2006	AV	
345	174	1/21/2006	AV	
	<u> </u>			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
			-		
		·			
	-				

S (INCLUDIN)	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
		DATE	EXMR		
East		6/20/2006	AV		
East		1/21/2006	AV		
	, .				